

# Analog Electronics

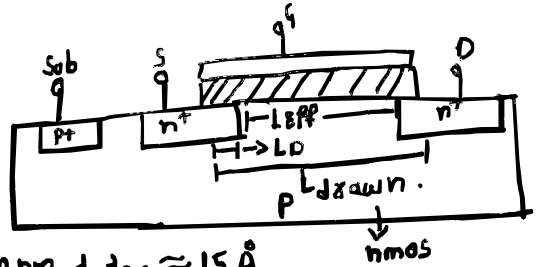
→ the level of abstraction of knowledge required to study analog design is Quantum physics → Solid state physics → Semiconductor device physics → device modelling → design of circuits.

## Mosfet as a switch

- if gate of n-mos is high → the resistance  $R_{DS}$  is low it conducts electricity
- if gate of n-mos is low → the resistance  $R_{DS}$  is high it act as open circuit

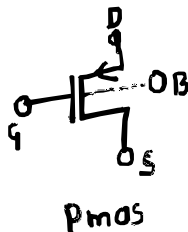
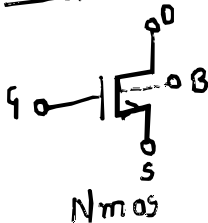
## Mosfet structure

$$L_{drawn} - 2L_D = L_{eff}$$



- \* typical value for  $L_{eff} \approx 10 \text{ nm}$  &  $t_{ox} \approx 15 \text{ \AA}$
- \* mosfet is symmetrical device
- \* the substrate should be reverse biased with respect to source & drain to prevent latch up
- \* Pmos is created by negating all the doping types
- \* Pmos is fabricated in an N-well & substrate is connected to highest potential ( $V_{DD}$ )

## Mosfet Symbol



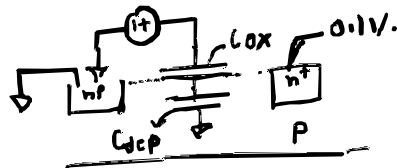
# Mosfet V-I characteristics

→ Threshold Voltage ( $V_{TH}$ )

\* As  $V_g$  becomes more +ve the holes in the substrate [nmos] get repelled from the gate hence the depletion region is formed

\* Increase  $V_g$  increase the width of the depletion region.

\* the channel can be modeled as two cap connected in series with voltage divider



\* the value of  $V_g$  the inversion of channel occurs is called  $V_{TH}$

\* if the value of  $V_g$  is increased further the charge in depletion region remain constant. while the channel charge density continuous to increase. which increase  $I_D$

$$* V_{TH} = \phi_{ms} + 2\phi_F + \frac{Q_{dep}}{C_{ox}}$$

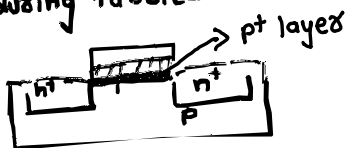
$\phi_{ms}$  → difference between workfunction of polysilicon & silicon substrate.

$$\phi_F \rightarrow \frac{kT}{q} \ln\left(\frac{N_{sub}}{n_i}\right)$$

$\Rightarrow k \rightarrow$  Boltzmann constant  
 $N_{sub} \rightarrow$  doping density of substrate.

$$\phi_{dep} \rightarrow \sqrt{4q\epsilon_{si}|\phi_F|N_{sub}} \quad \epsilon_{si} \rightarrow \text{dielectric constant of Si}$$

\* the  $V_{TH}$  of the mosfet is adjusted by adding dopent to the channel area during fabrication



## I-V characteristics of Mosfet

- \* the charge per unit length in mosfet is given

$$Q_0(x) = -C_{ox} W (V_{gs} - V_x - V_t)$$

where  $C_{ox} = \epsilon_0 / t_{ox}$

- \*  $I_d = Q_0 \times V$  where  $V \rightarrow$  Velocity of electron.

$$\therefore I_d = C_{ox} W (V_{gs} - V_x - V_t) V$$

we know that  $V = \mu E$  &  $E = -\frac{dV}{dx}$

$$\therefore I_d = C_{ox} W (V_{gs} - V_x - V_t) \mu \frac{dV}{dx}$$

$$\int_0^L I_d dx = \int_0^{V_{os}} C_{ox} W (V_{gs} - V_x - V_t) \mu dV$$

- \* the current in the channel is constant

$$\therefore I_d = C_{ox} \frac{W}{L} \mu \left[ (V_{gs} - V_t) V_{os} - \frac{V_{os}^2}{2} \right]$$

- \* the peak current is when  $V_{os} = V_{gs} - V_t \Rightarrow C_{ox} \frac{W}{L} \mu \left[ (V_{gs} - V_t) \frac{V_{os}^2}{2} \right]$

- \* we call  $V_{gs} - V_{th}$  as overdrive voltage.

- \*  $W/L \rightarrow$  aspect ratio

- \*  $V_{os} \leq V_{gs} - V_{th} \rightarrow$  triode region.

- \* If  $V_{os} \leq V_{gs} - V_{th}$  then  $I_d \approx C_{ox} \frac{W}{L} \mu_0 (V_{gs} - V_t) V_{os}$

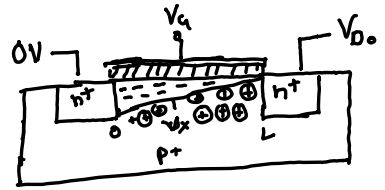
$$\& Ron = \frac{1}{C_{ox} \frac{W}{L} \mu_0 (V_{gs} - V_t)} \rightarrow \text{Voltage controlled resistor}$$

- \* the current becomes constant when  $V_{os} \geq V_{gs} - V_{th}$  this region

is called saturated region. and the channel becomes pinched off.

there will be current in the region after pinched off. due to the increase of velocity of electron in the pinched point. electron

Simply shoot to the drain of the device

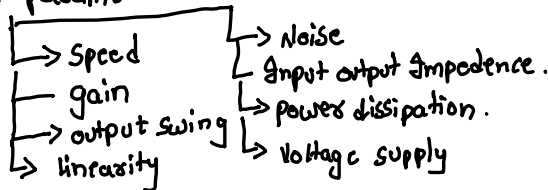


→ Ideal amplifier  $y(t) = a_0 + a_1 x(t)$

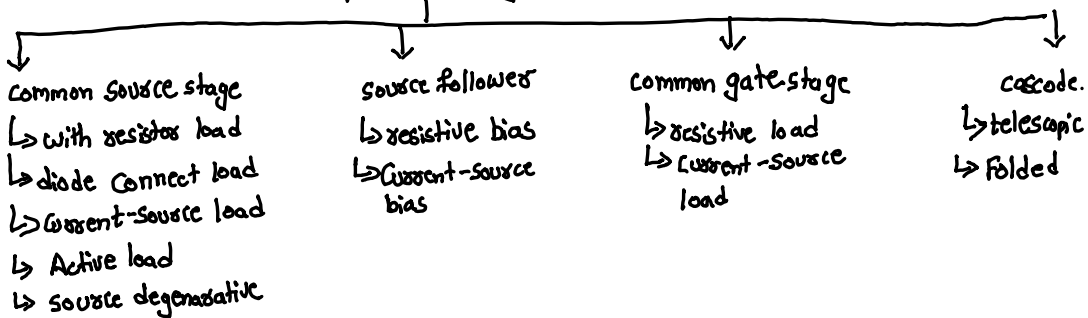
→ Real amplifier  $y(t) = a_0 + a_1 x(t) + a_2 x^2(t) \dots \dots$

↳ cause distortion

→ Performance parameters:-



### Amplifier categories



\* Common Source with resistor load

$$\rightarrow V_{out} = V_{DD} - R_L \times \frac{1}{2} \mu_0 C_{ox} \frac{W}{L} (V_{GS} - V_T)^2$$

$$\rightarrow \text{Swing range (output)} = V_{DD} \rightarrow V_{in} - V_T$$

$$\rightarrow \text{Input swing} = 0 \rightarrow V_{in} - V_T$$

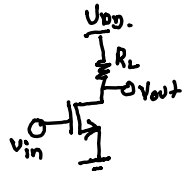
- for  $V_{in} > V_{in} - V_T \rightarrow$  mosfet is in triode region.

→ for triode region  $V_{out}$  is

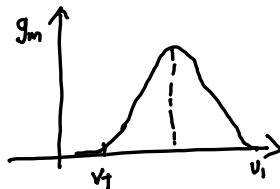
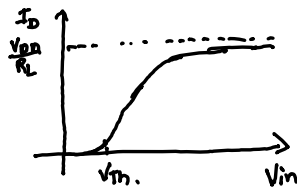
$$V_{out} = V_{DD} \times \frac{R_D}{R_L + R_D} = R_D \Rightarrow \mu_x C_{ox} \frac{W}{L} (V_{GS} - V_T)$$

$$\Rightarrow \text{gain } A_V = \frac{\partial V_{out}}{\partial V_{in}} = -R_L \mu_x C_{ox} \frac{W}{L} (V_{GS} - V_T) \Rightarrow -g_m R_L$$

→  $g_m$  change when we apply large signal i.e  $g_m$  depend on  $V_{in}$ .



graph



$$\text{Gain} = -g_m R_D \Rightarrow -\sqrt{2 \mu_n C_{ox} \frac{W}{L} I_D} \times \frac{V_D}{I_D}$$

$V_D \rightarrow$  voltage across resistor

To increase gain increase

- $\rightarrow W/L \rightarrow$  lead to increase in drain capacitance. & increase  $V_D$  which reduce the output swing (due to reduce in  $R_D$  due to increase in  $W$ ).
- $\rightarrow V_D$  constant  $I_D$  reduce  $\rightarrow$  increase in  $R_D$  which lead to increase in output time constant.

$\Rightarrow$  the channel length modulation become significant when we increase  $R_L$ .

$$V_{out} = V_{DD} - R_L \frac{K}{2} (V_{GS} - V_T)^2 (1 + \lambda V_{out}) \quad K \rightarrow C_{ox} W/L \mu_n$$

$$\frac{dV_{out}}{dV_{in}} = -R_L K (V_{GS} - V_T) (1 + \lambda V_{out}) - R_L \frac{K}{2} (V_{GS} - V_T)^2 \lambda \frac{V_{out}}{V_{in}}$$

$$A_v = -R_L g_m - \frac{R_L}{\delta_o} A_v \quad 1/\delta_o = K/2 (V_{GS} - V_T)^2 \lambda$$

$$A_v \approx g_m \frac{R_L \delta_o}{R_L + \delta_o} \Rightarrow -g_m (R_L \parallel \delta_o)$$

$\Rightarrow 1/g_m$  is very less than  $\delta_o$

$\rightarrow$  diode connected mosfet :- if drain is connected to gate.



$\therefore$  output impedance =  $1/g_m \parallel \delta_o \approx 1/g_m$

$$g_m V_x + \frac{V_x}{R} = I \Rightarrow \frac{I}{V_x} = g_m + \frac{1}{R_L} + g_{mb}$$

$$\Rightarrow \frac{1}{R_{eq}} = \frac{1}{\delta_m} + \frac{1}{R_L} + \frac{1}{\delta_{mb}}$$

→ If we neglect  $r_{ds}$  since it is large the equivalent resistance in

diode connect is  $\approx 1/g_m + g_{mb}$

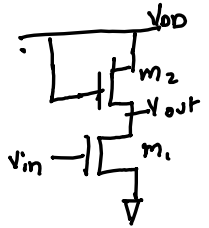
→ ∴ the gain of diode connect is  $A_v = -g_{m1} R_D$

$$= -g_{m1} \times \frac{1}{g_{m2} + g_{mb2}}$$

$$= \frac{-g_{m1}}{g_{m2}} \times \frac{1}{1 + \frac{g_{mb2}}{g_{m2}}} = \frac{-g_{m1}}{g_{m2}} \times \frac{1}{1+n} \quad n = \frac{g_{mb2}}{g_{m2}}$$

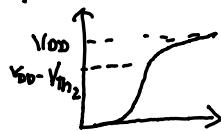
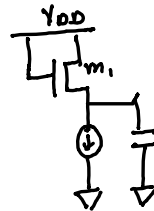
$$\Rightarrow \frac{\sqrt{2} \frac{W_1}{L_1} C_{ox} \mu_n I_{D1}}{\sqrt{2} \frac{W_2}{L_2} C_{ox} \mu_n I_{D2}} \times \frac{1}{1+n} \quad I_{D1} = I$$

$$= \frac{\sqrt{W_1/L_1}}{\sqrt{W_2/L_2}} \times \frac{1}{1+n}$$



→ If  $n$  is neglected bias is independent of bias current or voltage there for it is linear

→ if mosfet 1 is off  $I_D$  is zero the voltage will go to  $V_{DD}$ . during this time it will reach  $V_{DD} - V_{th2}$  fast then transistor turns off then it will go to  $V_{DD}$  slowly due to reverse bias current. ∴ for high speed application we can consider it will reach  $V_{DD} - V_{th2}$ .



→ gain is weak function of dimension we need to rise  $W_1/L_1 / W_2/L_2$  to 25 to get gain of 5.

→ In current technology channel length modulation is quite significant which can't be ignored

$$\therefore A_v = g_{m1} \times \left( \frac{1}{g_{m2}} \parallel r_{ds1} \parallel r_{ds2} \right)$$

\* common source with current source load.

$$\rightarrow g_{\text{ain}} = -g_m (\delta_1 \parallel \delta_2)$$

$\rightarrow$  if  $\delta_2$  is large  $g_{\text{ain}} = -g_m \delta_1$

$\rightarrow$  swing range  $= V_{\text{min}} = V_{\text{in}} - V_{Tn}$   $V_{\text{max}} = V_B - V_T$

$$\rightarrow g_{\text{ain}} = -g_m \delta_1$$

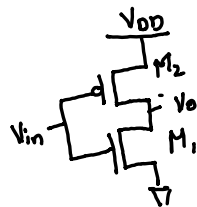
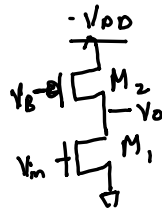
$$= -\sqrt{2 \times \frac{W}{L}} \mu_n C_{ox} I_D \times \frac{1}{\lambda I_D}$$

\* common source with active load.

$$\rightarrow A_v = -(g_{m1} + g_{m2}) (\delta_{o1} \parallel \delta_{o2})$$

$\rightarrow$  Issue with this configuration

$\rightarrow$  bias voltage are dependent on PVT. if there is mismatch it cause change in current.



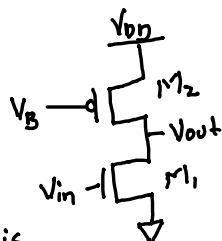
\* common source in triode region.

$\rightarrow$   $M_2$  is in triode region.

$$\rightarrow g_{\text{ain}} = -g_m (\delta_1 \parallel R_o)$$

$$\rightarrow R_o = \frac{1}{\mu_p C_{ox} \frac{W}{L} (V_{DD} - V_B - |V_{Tp}|)}$$

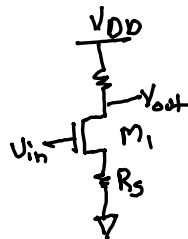
$\rightarrow$  drawback  $\rightarrow R$  depends on PVT like  $V_T$ ,  $W/L$ ,  $C_{ox}$  which is difficult to control & change with temperature.



\* common source with degenerative load

$\rightarrow$   $g_m$  is function of  $V_{GS}$  degenerative is used to make gain as weak function of  $V_{in}$ .

$\rightarrow$  It make circuit gain more linear.



$$g_{m(\text{new})} = \frac{d g_m}{d V_{in}} \Rightarrow \frac{\partial I_D}{\partial V_{GS}} \times \frac{\partial V_{GS}}{\partial V_{in}}$$

$$V_{gs} = V_{in} - I_D R_S \Rightarrow \frac{\partial V_{gs}}{\partial V_{in}} = 1 - \frac{\partial I_D}{\partial V_{in}} R_S.$$

$$\Rightarrow \frac{\partial I_D}{\partial V_{gs}} \times \frac{\partial V_{gs}}{\partial V_{in}} = \frac{\partial I_D}{\partial V_{gs}} \left( 1 - \frac{\partial I_D}{\partial V_{in}} R_S \right).$$

$$\Rightarrow g_{m(\text{new})} = g_{m(\text{old})} \left( 1 - g_{m(\text{new})} R_S \right).$$

after rearranging  $g_{m(\text{new})} = \frac{g_{m(\text{old})}}{1 + g_{m(\text{old})} R_S} \rightarrow$  Neglecting body effect

$\therefore$  small signal gain  $A_v = -g_m R_D \Rightarrow -g_{m(\text{new})} R_D$

$$\Rightarrow \frac{g_m \times R_D}{1 + g_m R_S} \rightarrow \text{Neglecting body effect.}$$

\* if  $R_S$  is increased  $g_m$  become weak function of  $g_m$  & if  $R_S \gg \frac{1}{g_m}$ .

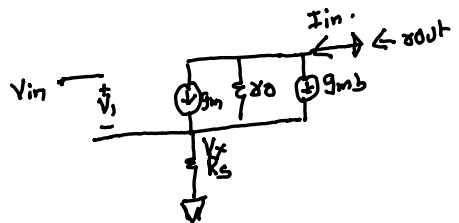
$$g_m \approx \frac{1}{R_S}$$

\* the drawback of this circuit is it reduce the gain of the circuit.

\* With body effect gain changes to

$$I_{in} = g_m V_i - g_{mb} V_x - \frac{I_{Dn} R_S}{\delta_o}$$

$$\frac{I_{in}}{V_{in}} \Rightarrow g_m = \frac{g_m \delta_o}{R_S + [1 + (g_m + g_{mb}) R_S] \delta_o}$$



$$\therefore A_v = -g_m R_D$$

$$V_{out} = R_S + [1 + (g_m + g_{mb}) R_S] \delta_o \quad \therefore R_{out} = \delta_{out} \parallel R_D$$

$$V_{out} \approx R_S + [(g_m + g_{mb}) R_S] \delta_o \quad \text{if } g_m g_{mb} R_S \gg 1.$$



## Source follower amplifiers

⇒ It act as a Voltage buffered

$$\Rightarrow \frac{1}{2} u_0 C_{ox} \frac{W}{L} (V_{in} - V_{out} - V_{th})^2 R_s = V_{out} \quad (1)$$

⇒ differentiating with respect to  $V_{in}$

$$\frac{1}{2} u_0 C_{ox} \frac{W}{L} 2 (V_{in} - V_{out} - V_{th}) R_s \left( 1 - \frac{\partial V_{out}}{\partial V_{in}} - \frac{\partial V_{th}}{\partial V_{in}} \right) = \frac{\partial V_{out}}{\partial V_{in}}$$

$$\Rightarrow \frac{\partial V_{th}}{\partial V_{in}} \Rightarrow \frac{\partial V_{th}}{\partial V_{SB}} \times \frac{\partial V_{SB}}{\partial V_{in}} \quad V_{SB} = +V_{out} \quad \frac{\partial V_{th}}{\partial V_{SB}} = \eta$$

$$\Rightarrow \frac{\partial V_{out}}{\partial V_{in}} = A_v = \frac{u_0 C_{ox} \frac{W}{L} (V_{in} - V_{th} - V_{out}) R_s}{1 + u_n C_{ox} \frac{W}{L} (V_{in} - V_{th} - V_{out}) R_s (1 + \eta)}$$

$$\Rightarrow g_m = u_n C_{ox} \frac{W}{L} (V_{in} - V_{th} - V_{out}) \rightarrow \text{by differentiation of 1.}$$

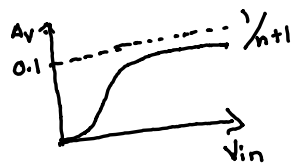
$$A_v = \frac{g_m R_s}{1 + g_m R_s (1 + \eta)}$$

$$A_v = \frac{g_m R_s}{1 + (g_m + g_{mb}) R_s}$$

Extra — — — — — x — — — — —

$$\begin{aligned} V_{GS} &= V_{in} - V_{th} \\ \frac{\partial V_{GS}}{\partial V_{th}} &= -1. \therefore g_m \times \eta = \frac{\partial V_{GS}}{\partial V_{th}} \times \frac{\partial V_{th}}{\partial V_{SB}} = -g_{mb} \\ \frac{\partial g_m}{\partial V_{SB}} &= \frac{\partial g_m}{\partial V_{GS}} = -1 \times -g_{mb} = g_{mb} \end{aligned}$$

⇒ even  $R_s \rightarrow \infty$  the gain of amplifier is always less than 1  $\therefore$  i.e.  $\frac{g_m}{g_m + g_{mb}}$



⇒ if  $V_{GS}$  is increased by the factor  $\sqrt{2}$  current in resistor increase by the factor of 2 this causes non-linearity to resolve this the resistor is replaced by constant current source which is in saturation.

$$I_{out} = \frac{1}{g_m + g_{mb}}$$

$$A_v = \frac{g_m}{g_m + g_{mb}}$$

